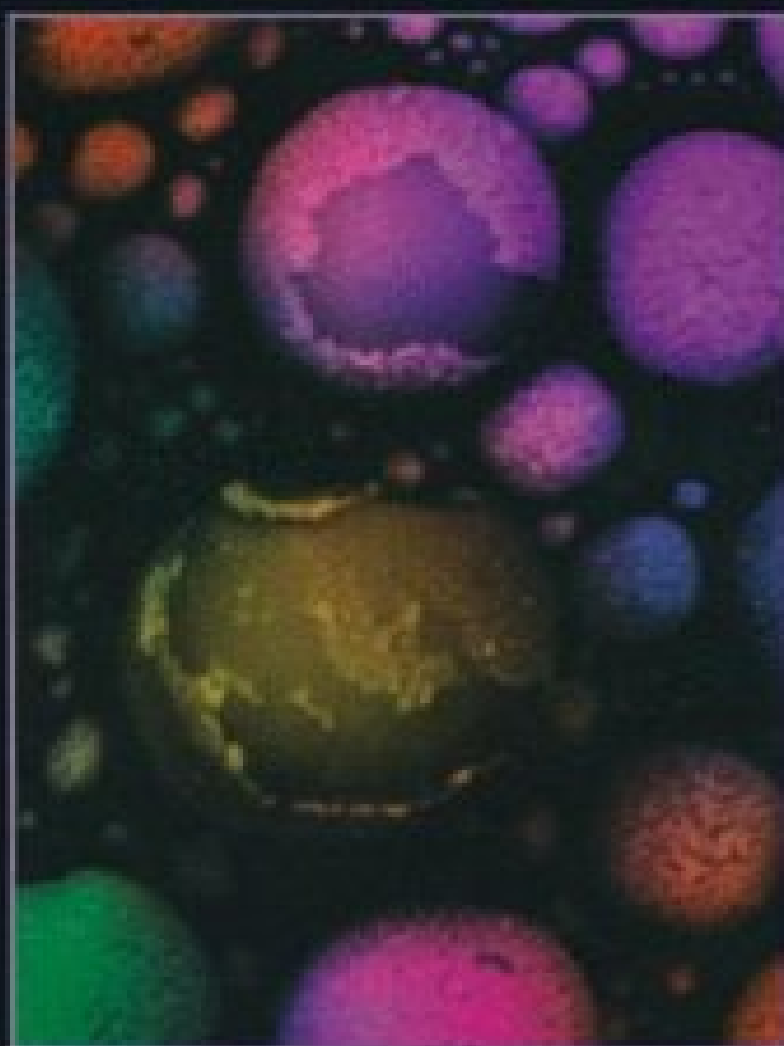


Scanning Electron Microscopy and X-Ray Microanalysis

THIRD EDITION



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Resumo de Scanning Electron Microscopy and X-Ray Microanalysis: Third Edition

This text provides students as well as practitioners with a comprehensive introduction to the field of scanning electron microscopy (SEM) and X-ray microanalysis. The authors emphasize the practical aspects of the techniques described.

Topics discussed include user-controlled functions of scanning electron microscopes and x-ray spectrometers and the use of x-rays for qualitative and quantitative analysis. Separate chapters cover SEM sample preparation methods for hard materials, polymers, and biological specimens.

In addition techniques for the elimination of charging in non-conducting specimens are detailed.

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